EIROforum Science-Business WAMAS Workshop on Advanced Materials and surface

SESSION I - SURFACE SCIENCE: Part II

Polyimide anisotropic chemical etching

CERN TE/MPE/EM section

Summary

- Novel Polyimide etching process
 - description
- Applications
 - HDI circuits
 - GEMs
 - Embedded silicon circuits

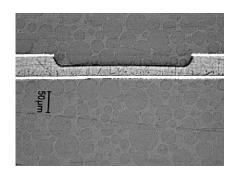
Some well known brand names for Polyimide: KAPTON from Dupont de Nemours APICAL from KANEKA UPILEX from UBE

Test description

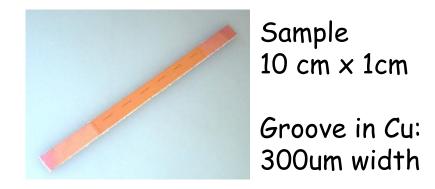
Samples:

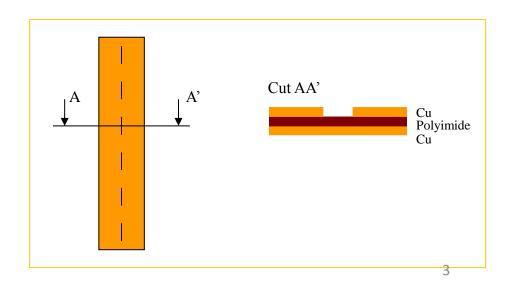
Polyimide 1 [5/50/5 um]
Polyimide 2 [5/25/5 um]
Polyimide 3 [5/25/0 um]
Polyimide 4 [25/25/25 um]

The etching of Polyimide is measured with micrographic pictures



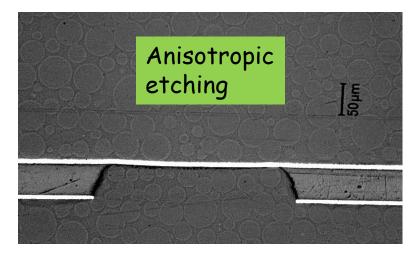
Strips used for measuring the Polyimide etching



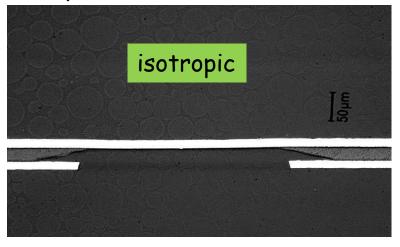


First results

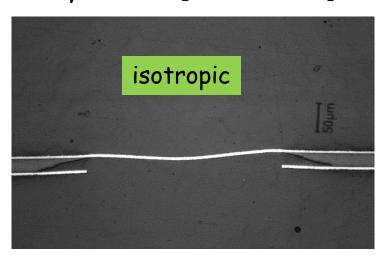
Polyimide 1 [5/50/5 um]



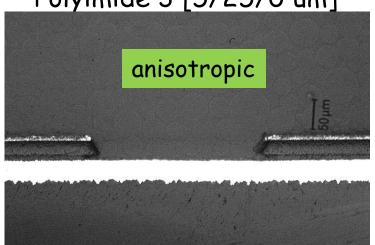
Polyimide 4 [25/25/25 um]



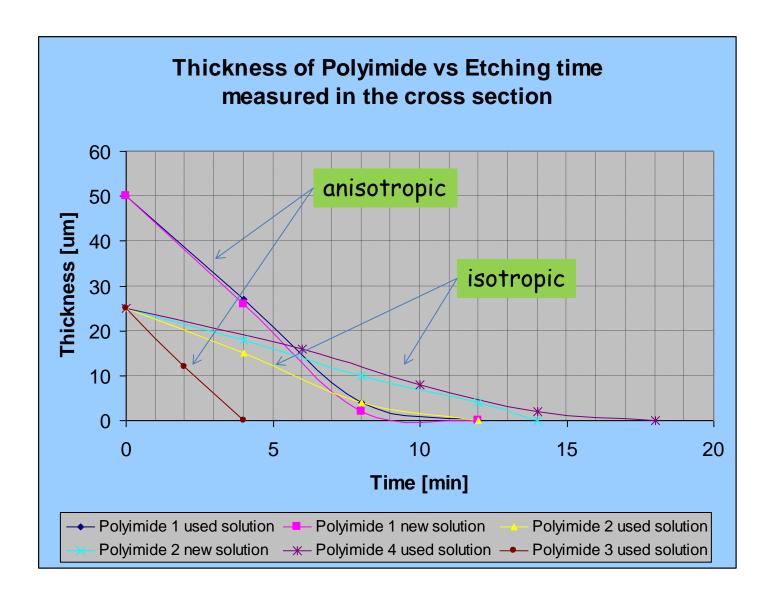
Polyimide 2 [5/25/5 um]



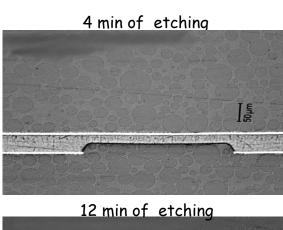
Polyimide 3 [5/25/0 um]

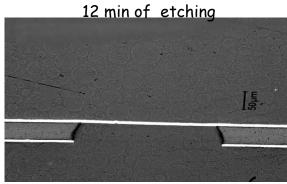


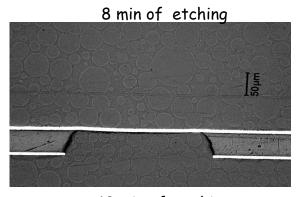
Polyimide etching

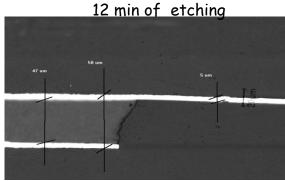


Most interesting sample: 1 [5/50/5 um]



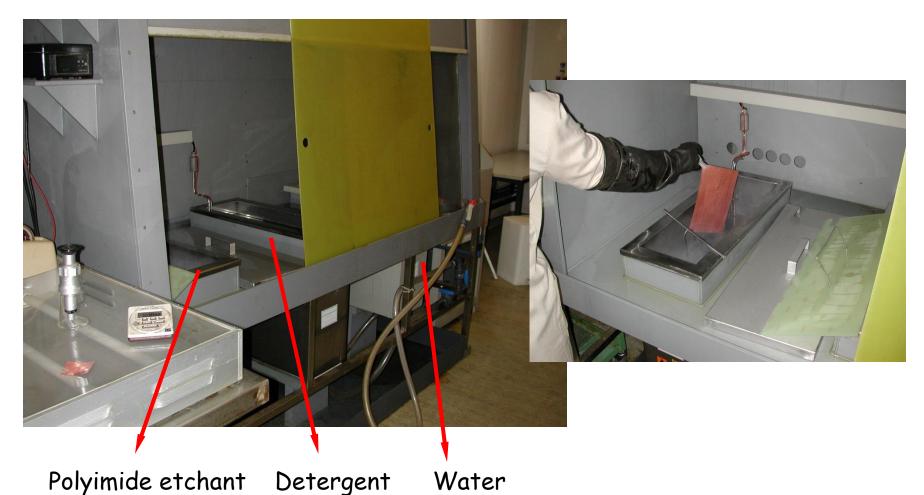






Highly anisotropic etching Micron level definition Wide process window

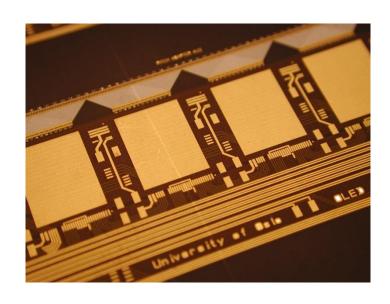
Equipment for PI etching

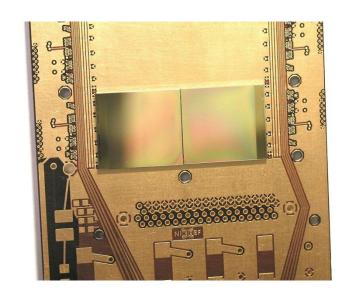


Summary

- Applications
 - HDI circuits
 - GEMs
 - Embedded silicon circuits

High Density Interconnect (HDI) circuits application

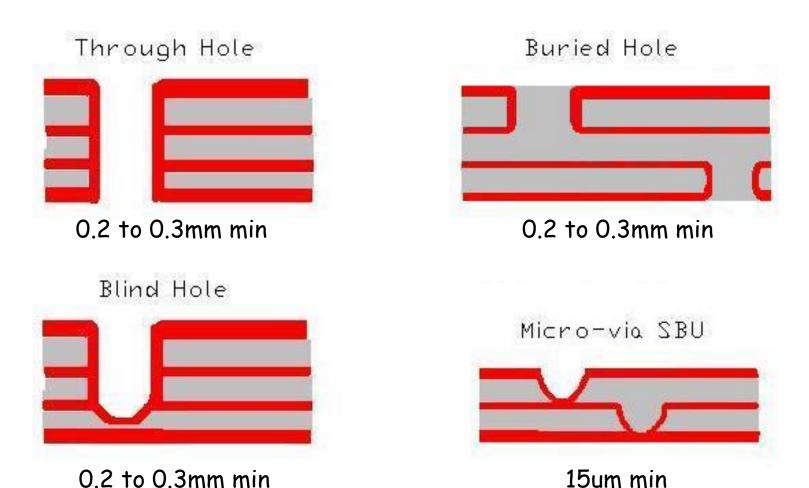




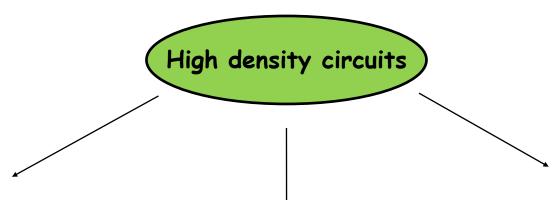
Atlas inner tracker front end module

R&D Multi chip detector module

High density interconnections are limited by the PTH size (Plated Through Holes)



HDI applications



Portable PCs Mobile phones Cameras

- -High volume
- -High R&D cost
- -Mass production Driven
- -Main players are defining machines& technologies

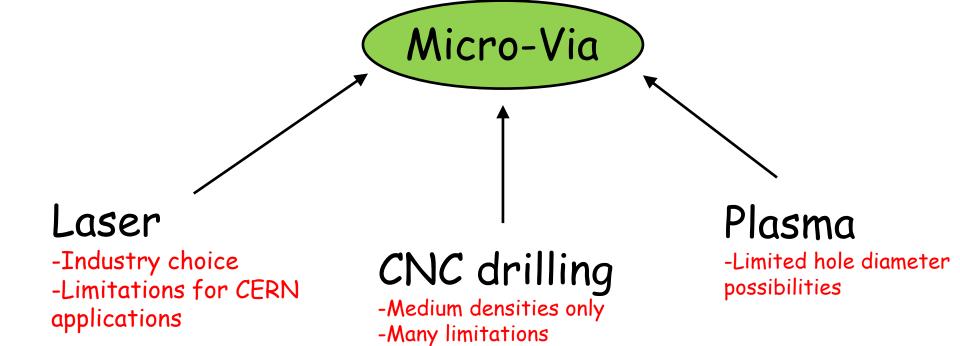
Industrial Applications

- -Low to Medium volume
- -Using High volume available techniques
- -No R&D possible
- -No possibility to influence main players choices

CERN inner tracker front end Electronics

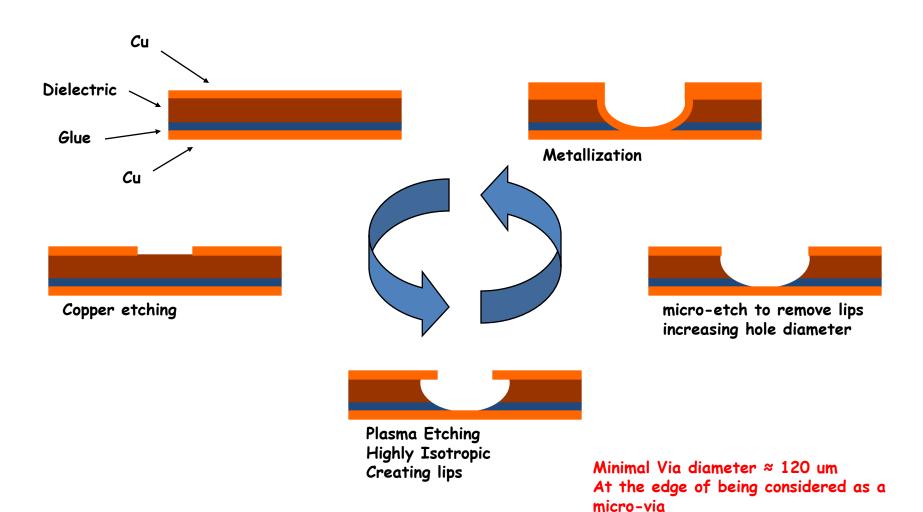
- -Low volume
- -Very Special features
- -CERN can't influence Main players choices

Micro-via processes existing in industry

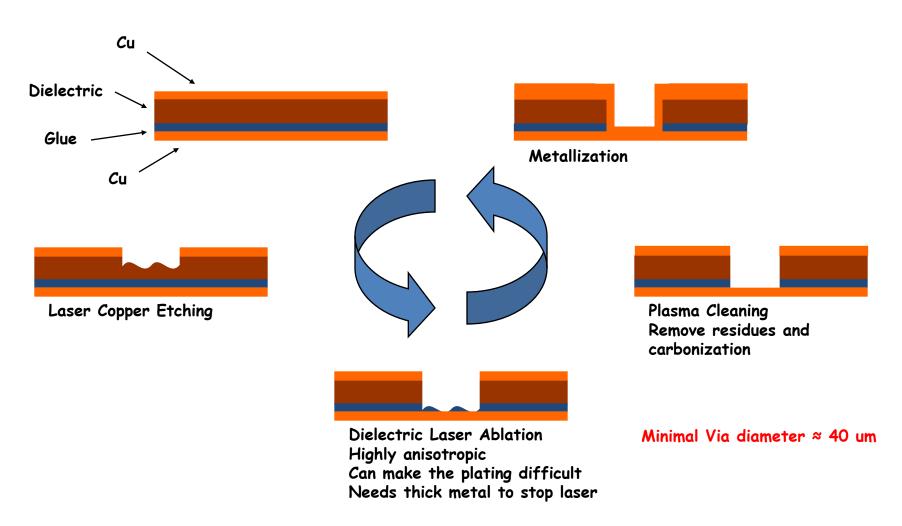


-Low speed

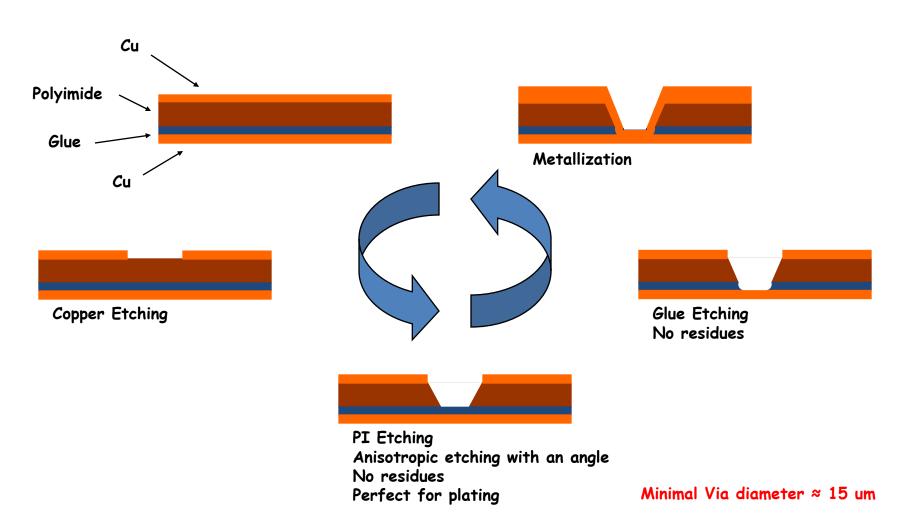
<u>Plasma</u>



Laser (Industry preferred technique)

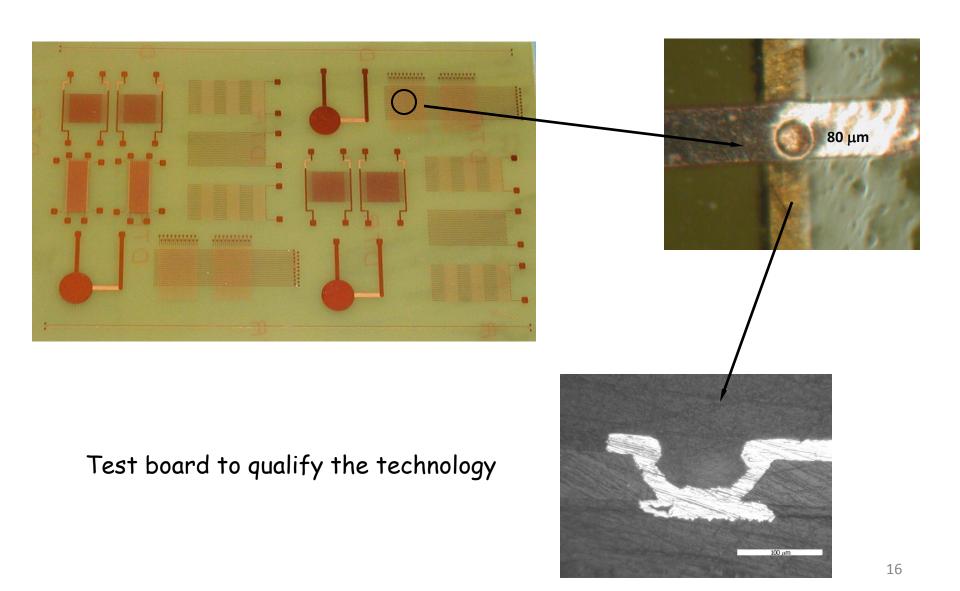


Chemical PI etching



15

Chemical micro-via



Why Chemical micro-via in HDI circuits:

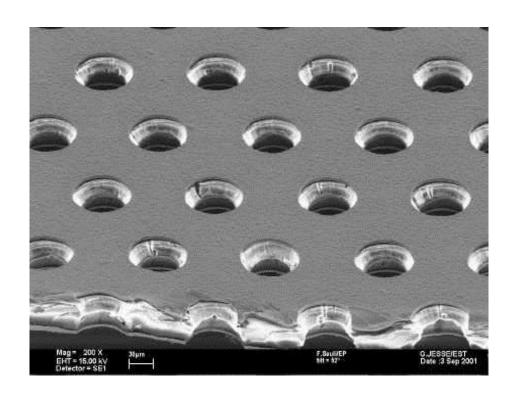
Advantages

- Highest connection density
- Best hole definition
- Low R&D cost
- Low production equipment cost
 - CERN set up < 100 KCHF
 - laser + plasma > 800KCHf
- Low maintenance cost
 - CERN set up→ chemistry cost
 - Laser \rightarrow 10% of the equipment cost/year

Disadvantages

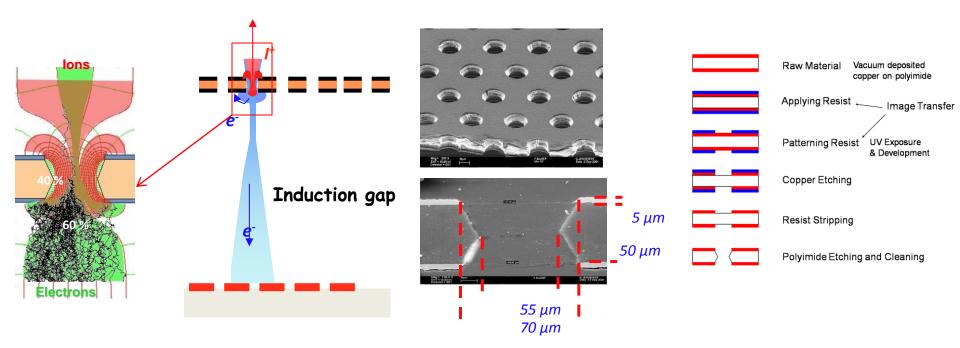
Only Adhesive-less metal vacuum deposited cladded polyimide

Gas electron multiplier (GEM) application



50um thick GEM SEM picture

<u>GEM</u>





Thin, metal coated polyimide foil perforated with high density micron level accuracy holes pattern.

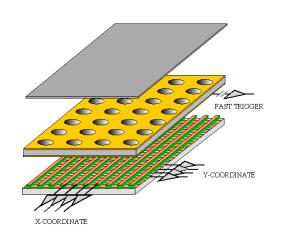
Electrons are collected on a patterned readout board.

A fast signal can be detected on the lower GEM electrode for triggering or energy discrimination.

All readout electrodes are at ground potential.

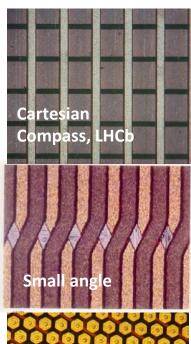
Positive ions partially collected on the GEM electrodes.

GEM detector

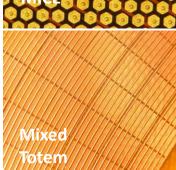


Full decoupling of the charge amplification structure from the charge collection board.

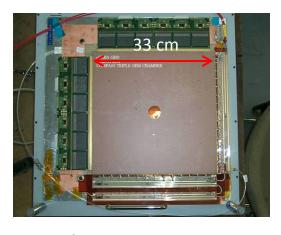
Both structures can be optimized independently!







A. Bressan et al, Nucl. Instr. and Meth. A425(1999)254

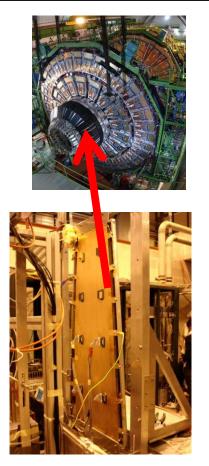


Compass

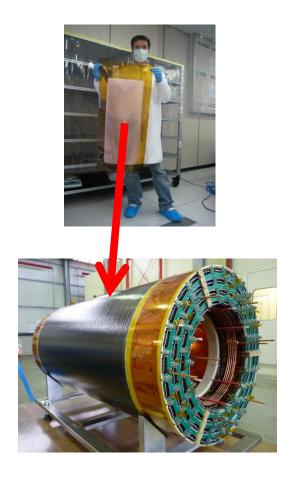
Totem

Both detectors use three GEM foils in cascade for amplification to reduce discharge probability by reducing field strength.

GEM detectors: planar & cylindrical



•GEM 1.1m x 500mm
•CMS GEM detector GE1/1



- ·KLOE Cylindrical 3 GEM Detector
- •GEM 800mm x 500mm
- ·Read-out 2D: 800mmx 500mm

Why Chemical micro-via in GEM?

- One GEM needs up to 1x10⁸ holes in a foil (1m x 0.5m)
- 8 min process with chemical process
- 138 hours with a modern laser (200Holes/sec).
 - And still hole shape and carbonisation problems
- Not possible with the other techniques.
 - Hole too large with plasma (min 120um)
 - 3 years to drill one foil with a CNC machine (1 hole/sec)

Embedded silicon circuits application

CERN needs special circuits near interaction points:

- -Low mass to avoid multiple scattering
- -Radiation hard, Long term reliability
- -High density of interconnection



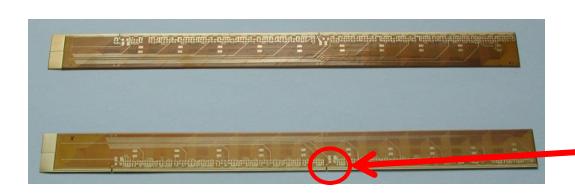
Ex: CMOS pixel detector embedded in Polyimide flex

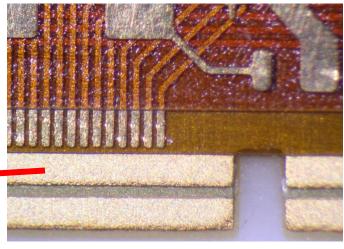
Low mass aspect

Material	Radiation length	Density	Resistivity
	[cm]	[gr/cc]	[uohms*cm]
Gold	0.3	19.3	2.4
Copper	1.4	9.0	1.7
Aluminum	8.9	2.7	2.7
Glass epoxy	19.4		
Polyimide	29.0		
Beryllium	35.3	1.9	3.3

Copper is close to 6.5 times less transparent than aluminum And aluminum has only 1.6 times the resistivity of copper Polyimide is 1.5 times better than glass epoxy.

5 Al layers ALICE Pixel Bus





Via: 100um

5 Aluminum layers

10um Vacuum deposited aluminum for signals 50um laminated aluminum layer for power

100um line and 50um space
12um polyimide layers
Size 160mm x 16mm
Staircase shape on one side for bonding

Full Aluminium circuit: Multiple scattering solved

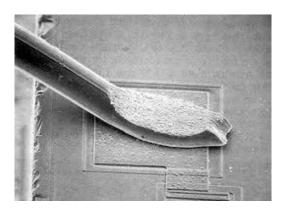
8 layer ATLAS IBL Al/Cu mixed multilayer

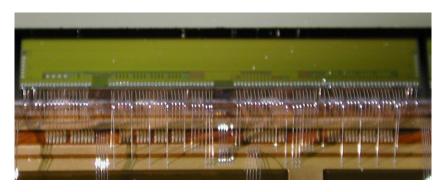


Via min: 300um
5 Copper signal layers
2 x50um laminated aluminum layer for power
70um line and 50um space
25um polyimide layers
Pure epoxy gluing
Size 400mm x 20mm
200 to 300 Mrad compatible

Only pure epoxy and PI: Radiation damage solved

Usual Chip to flex electrical connection technique: wire bonding





2 to 3mm Dead zone

Peripheral connection introducing dead zones

Needs mechanical and humidity protection (AL/Au glob top)

Conventional Bonding limits the density and needs protection.

Multiple scattering problem is solved Radiation problem is solved



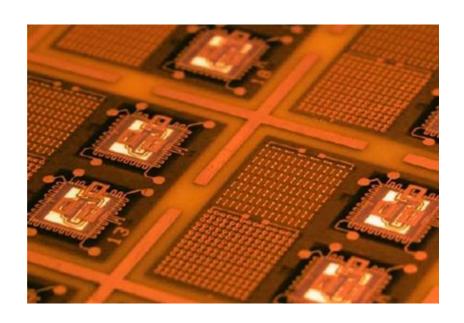
Embedding the silicon chip in a special HDI flex:

-Remove bonding and use micro-via for connections

-Use PI dielectric and epoxy glue for their resistance to radiations

-Use Aluminum tracks to limit multiple scattering

Embedded Chip situation in industry



Solder mask

Flip-chip

Chip

Build-up

Adhesive

Multilayer

Laser micro-via 100um via Copper strips

Problems:

Thick copper pads on chip (15um) to avoid laser damage during drilling.

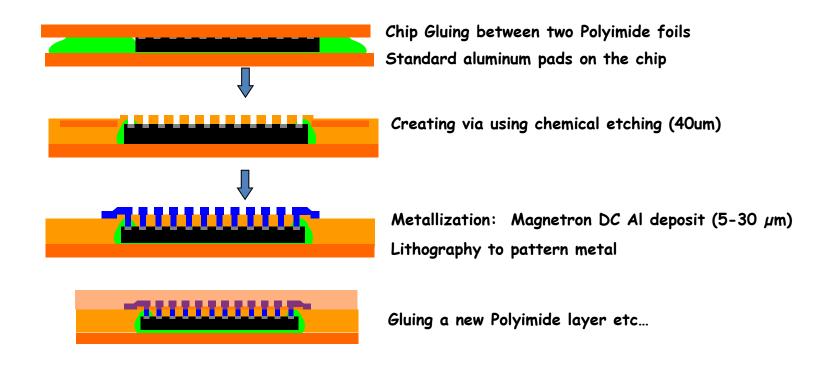
Wafer level post processing needed (large volume only).

Prohibitive R&D cost.

Only Copper system available in industry.

CERN needs Aluminum strips.

CERN chip embedding principle



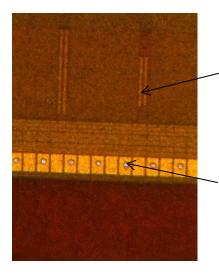
- No possible damage of the chip during micro via creation
- No post processing of the chip needed The standard metal is sufficient

Example



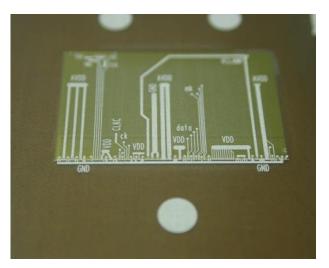
Solid state 50um silicon flexible sensor wrapped over cylindrical shape (R=20 mm)



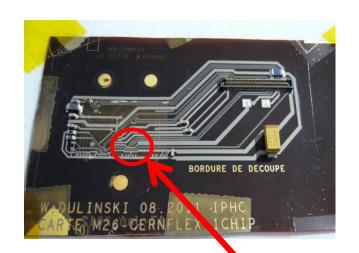


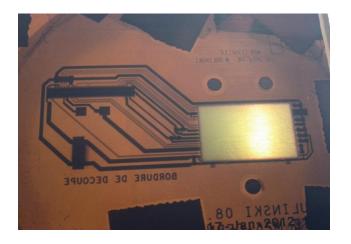
Solid state sensor embedded in Polyimide

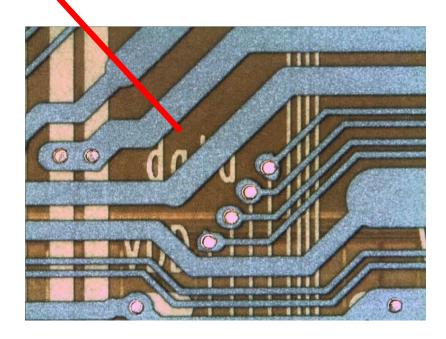
40um via Before Al Plating on 80um pads



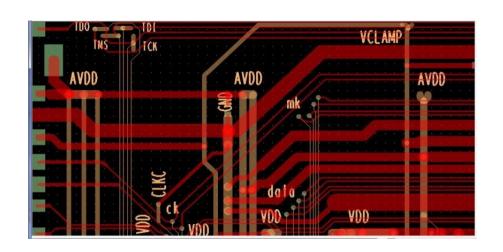
Same example with 2 aluminum layers



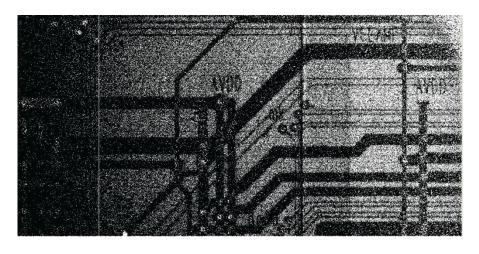




Auto-radiography test



Lithography details of interconnecting metal (two layers of ~10 μ m thick Al) deposited on top of the pixel sensor



Auto-radiography of metal measured by pixel sensor itself using 5.9 keV Xrays (55Fe)

Why Chemical Via with embedded chips:

Advantages:

- Low R&D cost
- No chip post processing needed
- Ultimate integration, no dead zones
- PI Provides a mechanical and chemical protection
- Low mass aluminium compatible
- Rad hard
- This technology closes the gap between integrated circuits and PCBs

Disadvantages

No repair possible, inherent to Embedded technology

Conclusion

- The wet Polyimide etching is giving us a lot of possibilities (not all presented).
 - It as already triggered 4 patents
 - Close to 10 companies are already licensed for production
- Simple R&D set up and also good candidate for mass production.
- All the applications are not yet fully explored ex: microfluidic channels and embedded micro cooling structures.

Thank you